

#### N-CHANNEL ENHANCEMENT MODE MOSFET WITH SCHOTTKY DIODE

### **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	$I_D$ max $T_A = 25$ °C (Note 5)		
30V	12.5mΩ @ V <sub>GS</sub> = 10V	11.7A		
	14.8mΩ @ V <sub>GS</sub> = 4.5V	10.8A		

#### **Features**

- DIOFET utilizes a unique patented process to monolithically integrate a MOSFET and a Schottky in a single die to deliver:
  - Low R<sub>DS(ON)</sub> minimizes conduction losses
  - Low V<sub>SD</sub> reducing the losses due to body diode conduction
  - Low Q<sub>rr</sub> lower Q<sub>rr</sub> of the integrated Schottky reduces body diode switching losses
  - Low gate capacitance (Q<sub>g</sub>/Q<sub>gs</sub>) ratio reduces risk of shootthrough or cross conduction currents at high frequencies
  - Avalanche rugged I<sub>AR</sub> and E<sub>AR</sub> rated
- Lead Free, RoHS Compliant (Note 1)
- "Green" Device (Note 2)
- Qualified to AEC-Q101 Standards for High Reliability

### **Description and Applications**

This new generation MOSFET has been designed to minimize the onstate resistance ( $R_{DS(on)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- DC-DC Converters
- Power management functions

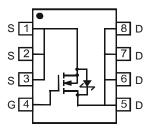
### **Mechanical Data**

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram Below
- Weight: 0.072 grams (approximate)





Top View



Top View Internal Schematic

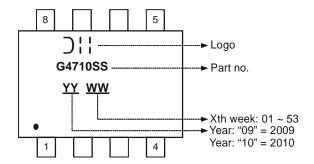
### Ordering Information (Note 3)

Part Number	Case	Packaging
DMG4710SSS-13	SO-8	2500 / Tape & Reel

Notes:

- 1. No purposefully added lead.
- 2. Diodes Inc.'s "Green" policy can be found on our website at http://www.diodes.com.
- 3. For packaging details, go to our website at http://www.diodes.com.

## **Marking Information**





## Maximum Ratings @TA = 25°C unless otherwise specified

Character	Symbol	Value	Unit		
Drain-Source Voltage			V <sub>DSS</sub>	30	V
Gate-Source Voltage			V <sub>GSS</sub>	±12	V
Continuous Drain Current (Note 4) V <sub>GS</sub> = 10V	Steady State	TA = 25°C TA = 85°C	I <sub>D</sub>	8.8 6.3	А
Continuous Drain Current (Note 5) V <sub>GS</sub> = 10V	$t \le 10 \text{ sec}$	TA = 25°C TA = 85°C	I <sub>D</sub>	11.7 8.5	А
Continuous Drain Current (Note 5) $V_{GS} = 4.5V$ $t \le 10 \text{ sec}$ $TA = 25^{\circ}C$ $TA = 85^{\circ}C$			I <sub>D</sub>	10.8 7.8	А
Pulsed Drain Current (Note 6)	I <sub>DM</sub>	90	Α		
Avalanche Current (Notes 6 & 7)			I <sub>AR</sub>	13	Α
Repetitive Avalanche Energy (Notes 6 & 7) L = 0.3mH			E <sub>AR</sub>	25.4	mJ

### **Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Power Dissipation (Note 4)	P <sub>D</sub>	1.54	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = 25°C (Note 4)	$R_{\theta JA}$	81	°C/W
Power Dissipation (Note 5)	P <sub>D</sub>	2.8	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = 25°C (Note 5)	$R_{\theta JA}$	45	°C/W
Operating and Storage Temperature Range	$T_{J}, T_{STG}$	-55 to +150	°C

## Electrical Characteristics @ T<sub>A</sub> = 25°C unless otherwise stated

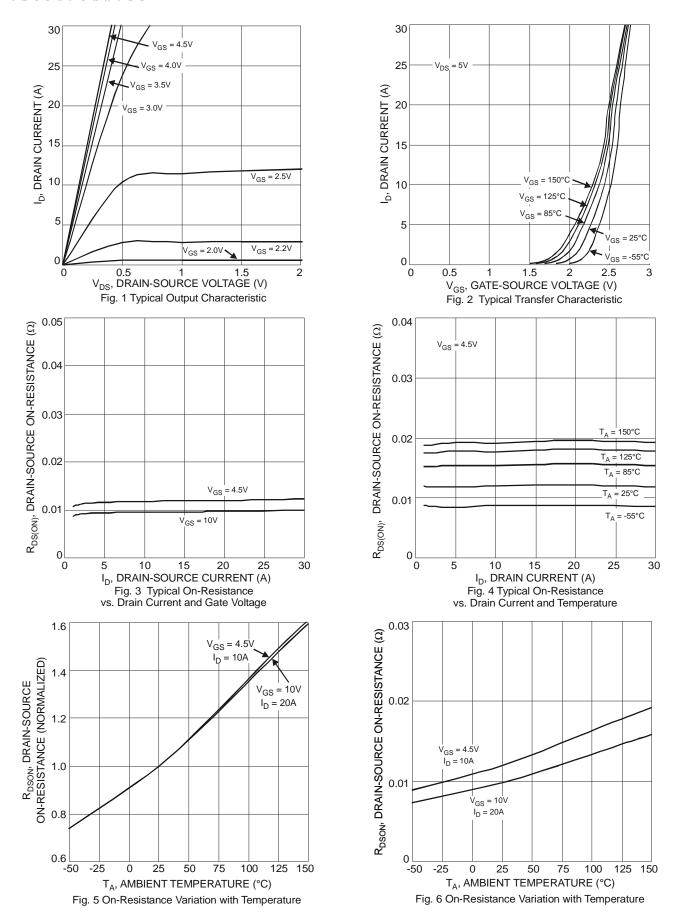
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	-	V	$V_{GS} = 0V$ , $I_D = 1mA$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	-	-	0.1	mA	$V_{DS} = 30V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±100	nA	$V_{GS} = \pm 12V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	$V_{GS(th)}$	1.0	-	2.3	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
Static Drain-Source On-Resistance		-	9.5	12.5	mΩ	$V_{GS} = 10V, I_D = 11.7A$	
Static Drain-Source Off-Resistance	R <sub>DS (ON)</sub>	-	11.5	14.8	111 2 2	$V_{GS} = 4.5V, I_D = 10.8A$	
Forward Transfer Admittance	Y <sub>fs</sub>	-	22	-	S	$V_{DS} = 5V, I_{D} = 11.7A$	
Diode Forward Voltage	$V_{SD}$	-	0.38	0.6	V	$V_{GS} = 0V, I_{S} = 1A$	
Maximum Body-Diode + Schottky Continuous Current	IS	-	-	5	Α	-	
DYNAMIC CHARACTERISTICS (Note 9)				-			
Input Capacitance	C <sub>iss</sub>	-	1849	-	pF	15)/ )/ 0)/	
Output Capacitance	Coss	-	158	-	pF	$V_{DS} = 15V, V_{GS} = 0V,$ of = 1.0MHz	
Reverse Transfer Capacitance	$C_{rss}$	-	123	-	pF	1 – 1.01011 12	
Gate Resistance	$R_{g}$	0.54	2.68	4.82	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$	
Total Gate Charge V <sub>GS</sub> = 4.5V	Qg	-	18.5	-	nC		
Total Gate Charge V <sub>GS</sub> = 10V	Qg	-	43	-	nC	$V_{DS} = 15V, V_{GS} = 10V,$	
Gate-Source Charge	Qgs	-	4.7	-	nC	I <sub>D</sub> = 11.7A	
Gate-Drain Charge	$Q_{gd}$	-	4.0	-	nC		
Turn-On Delay Time	t <sub>D(on)</sub>	-	6.62	-	ns		
Turn-On Rise Time	t <sub>r</sub>	-	8.73	-	ns	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 10V,	
Turn-Off Delay Time	t <sub>D(off)</sub>	-	36.41	-	ns	$R_G = 3\Omega$ , $R_L = 1.2\Omega$	
Turn-Off Fall Time	t <sub>f</sub>	-	4.69	-	ns	1	

4. Device mounted on FR-4 PCB with minimum recommended pad layout. The value in any given application depends on the user's specific board design.

5. Device mounted on 1" x 1" FR-4 PCB with high coverage 1 oz. Copper, single sided , device is measured at t ≤ 10 sec.

S. Device intollined of T X T TAP TO Built Inflight Coverage T 02. Copper, single side.
Repetitive rating, pulse width limited by junction temperature.
I<sub>AR</sub> and E<sub>AR</sub> rating are based on low frequency and duty cycles to keep T<sub>J</sub> = 25°C
Short duration pulse test used to minimize self-heating effect.
Guaranteed by design. Not subject to production testing.







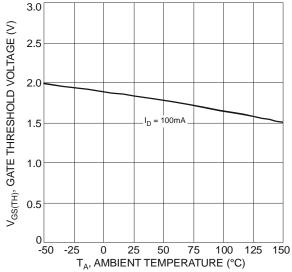
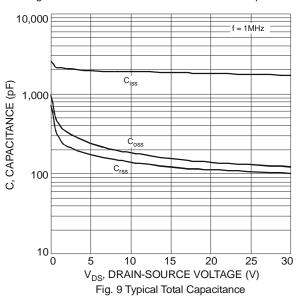
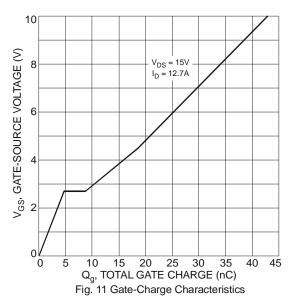
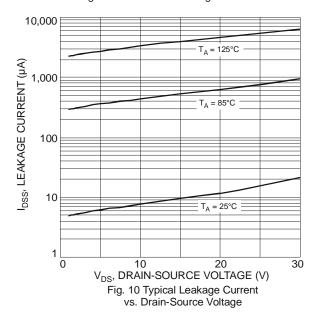


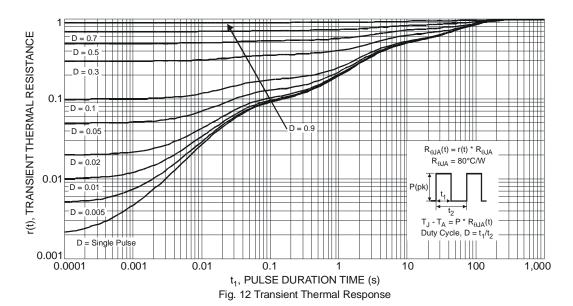
Fig. 7 Gate Threshold Variation vs. Ambient Temperature



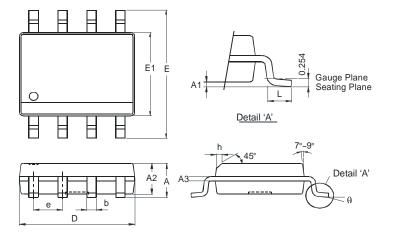






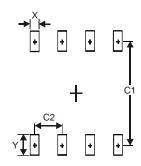


# **Package Outline Dimensions**



SO-8					
Dim	Min	Max			
Α	-	1.75			
<b>A</b> 1	0.10	0.20			
A2	1.30	1.50			
A3	0.15	0.25			
b	0.3	0.5			
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85	3.95			
е	1.27 Typ				
h	-	0.35			
L	0.62	0.82			
θ	0°	8°			
All Dimensions in mm					

## **Suggested Pad Layout**



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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